

LCIE SUD EST
Laboratoire de Moirans
Z.I. Centr'Alp
170, Rue de Chatagnon
38430 MOIRANS - FRANCE

CONDUCTED AND RADIATED MEASUREMENT PHOTO

FCCID: XKB-AXIPRTBT

1.1 Conducted emission



Test setup - Configuration 1



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Test setup - Configuration 2



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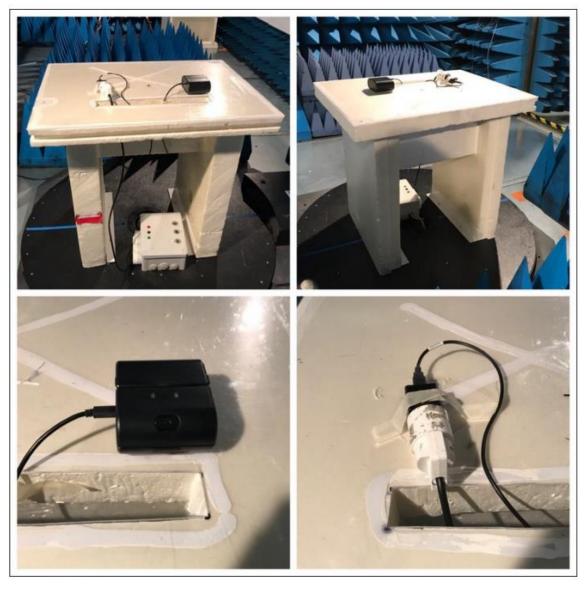
1.2 Radiated emissions



Test setup in anechoic chamber - Charging mode Cfg1 (<1Ghz) - EMC test setup



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Test setup in anechoic chamber - Charging mode Cfg2(<1GHz) - EMC test setup



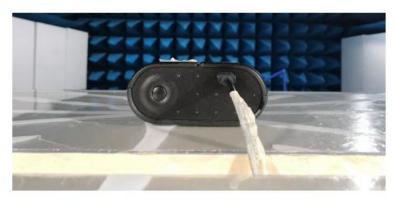
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Test setup in anechoic chamber - Battery mode Cfg3(<1GHz) - EMC test setup



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Test setup in anechoic chamber – Test setup (>1Ghz) -Configuration 4 DTM Test Mode



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Test setup in OATS - Charging mode Cfg1 (<1Ghz) - EMC test setup



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Test setup in OATS - Charging mode Cfg2(<1GHz) - EMC test setup